

FMOSTHU25N06-Q1-H

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FMOSTHU25N06-Q1-H

25A 60V N-Channel Trench
Enhancement Mode Power MOSFET

Features

- $V_{DS} = 60V$, $I_D = 25A$.
- $R_{DS(ON)} \leq 36m\Omega$, @ $V_{GS} = 10V$, $I_D = 12A$.
- $R_{DS(ON)} \leq 45m\Omega$, @ $V_{GS} = 4.5V$, $I_D = 7A$.
- Fast switching.
- Qualified to AEC-Q101 standard for high reliability.
- Lead-free parts meet RoHS requirements.
- Halogen-free (IEC61249-2-21) .

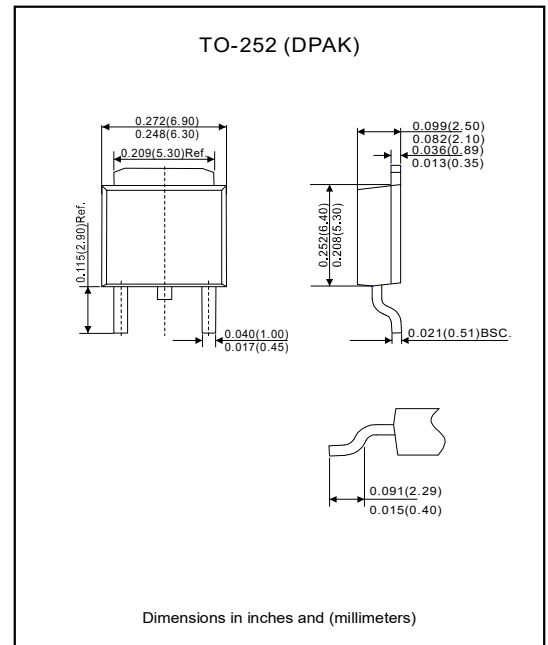
Applications

- LED lamp.
- Load switch.
- Uninterruptible power supply.

Mechanical data

- Epoxy:UL94-V0 rated flame retardant.
- Case : Molded plastic, TO-252 (DPAK).
- Terminals : Solder plated, solder able per MIL-STD-750, Method 2026.
- Mounting Position : Any.

Package outline

Maximum ratings (At $T_J = 25^\circ C$ unless otherwise noted)

Parameter	Symbol	Ratings	Unit
Drain-source voltage	V_{DS}	60	V
Gate-source voltage	V_{GS}	± 20	V
Continuous drain current ($T_c = 25^\circ C$)	I_D	25	A
Pulsed drain current (Note 1)	I_{DM}	62	A
Power dissipation ($T_c = 25^\circ C$)	P_D	37.5	W
Thermal resistance, junction to ambient	$R_{\theta JA}$	62	$^\circ C/W$
Thermal resistance, junction to case	$R_{\theta JC}$	4	$^\circ C/W$
Junction temperature	T_J	+175	$^\circ C$
Storage temperature range	T_{STG}	-55 to +175	

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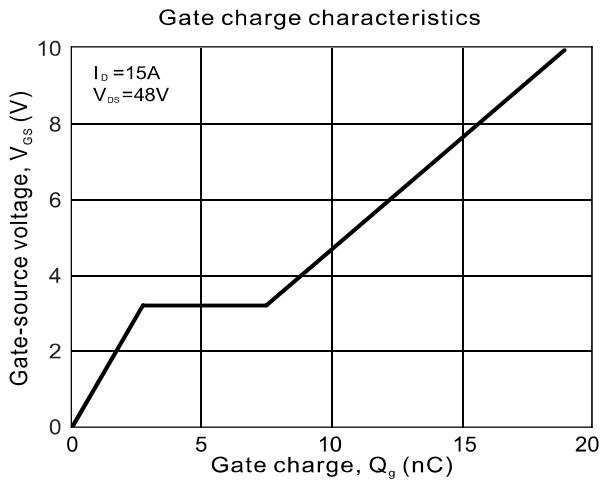
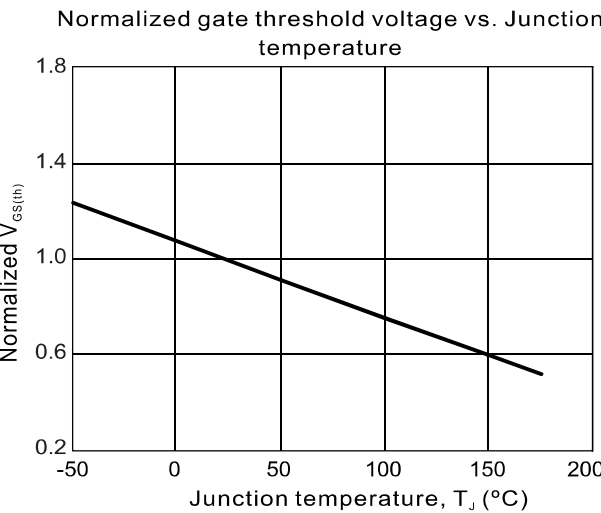
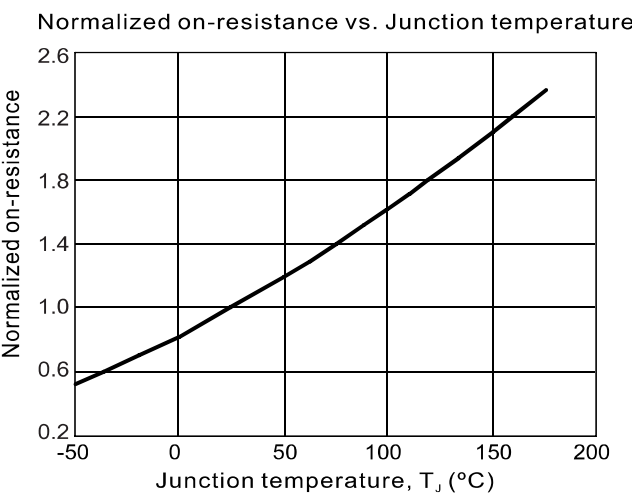
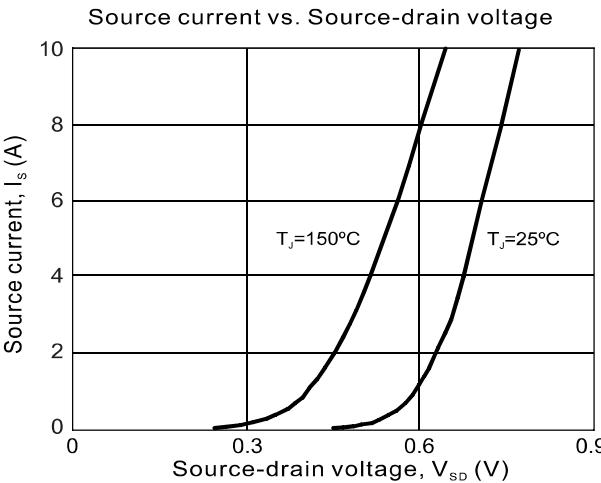
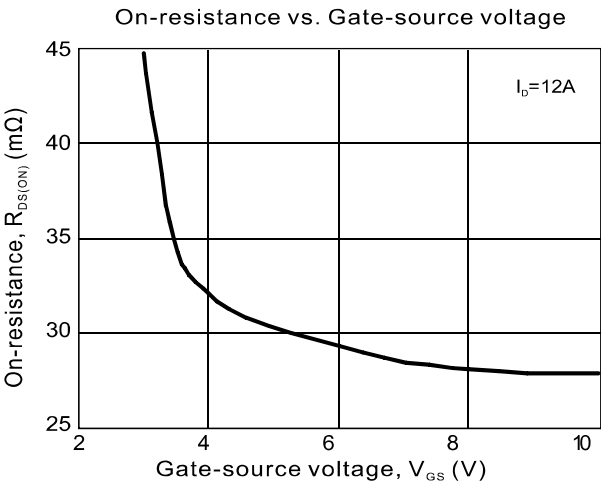
Electrical characteristics (At $T_J=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Off characteristics						
Drain-source breakdown voltage	BV _{DSS}	I _D =250μA, V _{GS} =0V	60			V
Drain-source leakage current	I _{DSS}	V _{DS} =48V, V _{GS} =0V			1	μA
Gate-source leakage current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V			±100	nA
On characteristics						
Gate threshold voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	1.2		2.5	V
Static drain-source on-state resistance	R _{DS(ON)}	V _{GS} =10V, I _D =12A			36	mΩ
		V _{GS} =4.5V, I _D =7A			45	
Dynamic parameters						
Input capacitance	C _{iss}	V _{GS} =0V, V _{DS} =15V, f=1.0MHz		1027		pF
Out capacitance	C _{oss}			65		
Reverse transfer capacitance	C _{rss}			46		
Gate resistance	R _g	V _{GS} =0V, V _{DS} =0V, f=1.0MHz		2.5		Ω
Switching parameters						
Total gate charge	Q _g	V _{GS} =10V, V _{DS} =48V, I _D =15A		19		nC
Gate to source charge	Q _{gs}			2.5		
Gate to drain charge	Q _{gd}			5		
Turn-on delay time	t _{d(on)}	V _{GS} =10V, V _{DD} =30V, I _D =15A, R _g =3.3Ω		2.8		ns
Rise time	t _r			16.6		
Turn-off delay time	t _{d(off)}			21.2		
Fall time	t _f			5.6		
Source-drain diode ratings and characteristics						
Drain-source diode forward voltage (Note2)	V _{SD}	I _S =1A, V _{GS} =0V			1.2	V
Maximum body-diode continuous current	I _S	V _G =V _D =0V, force current			20	A
Body diode reverse recovery time	t _{rr}	I _F =15A, dI _F /dt =100A/μs		12.2		nS
Body diode reverse recovery charge	Q _{rr}			7.3		nC

Notes : 1. Repetitive rating: pulsed width limited by maximum junction temperature.
2. The data tested by pulsed, pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
3. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

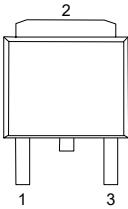
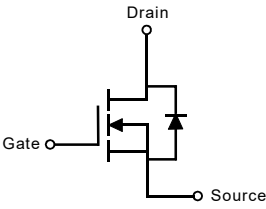
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Rating and characteristic curves



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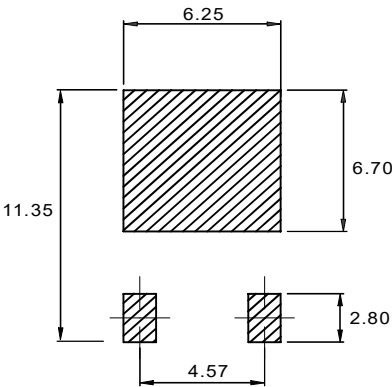
Pinning information

Pin	Simplified outline	Symbol
Pin 1 Gate Pin 2 Drain Pin 3 Source		

Marking

Type Number	Marking code
FMOSTHU25N06-Q1-H	NG036

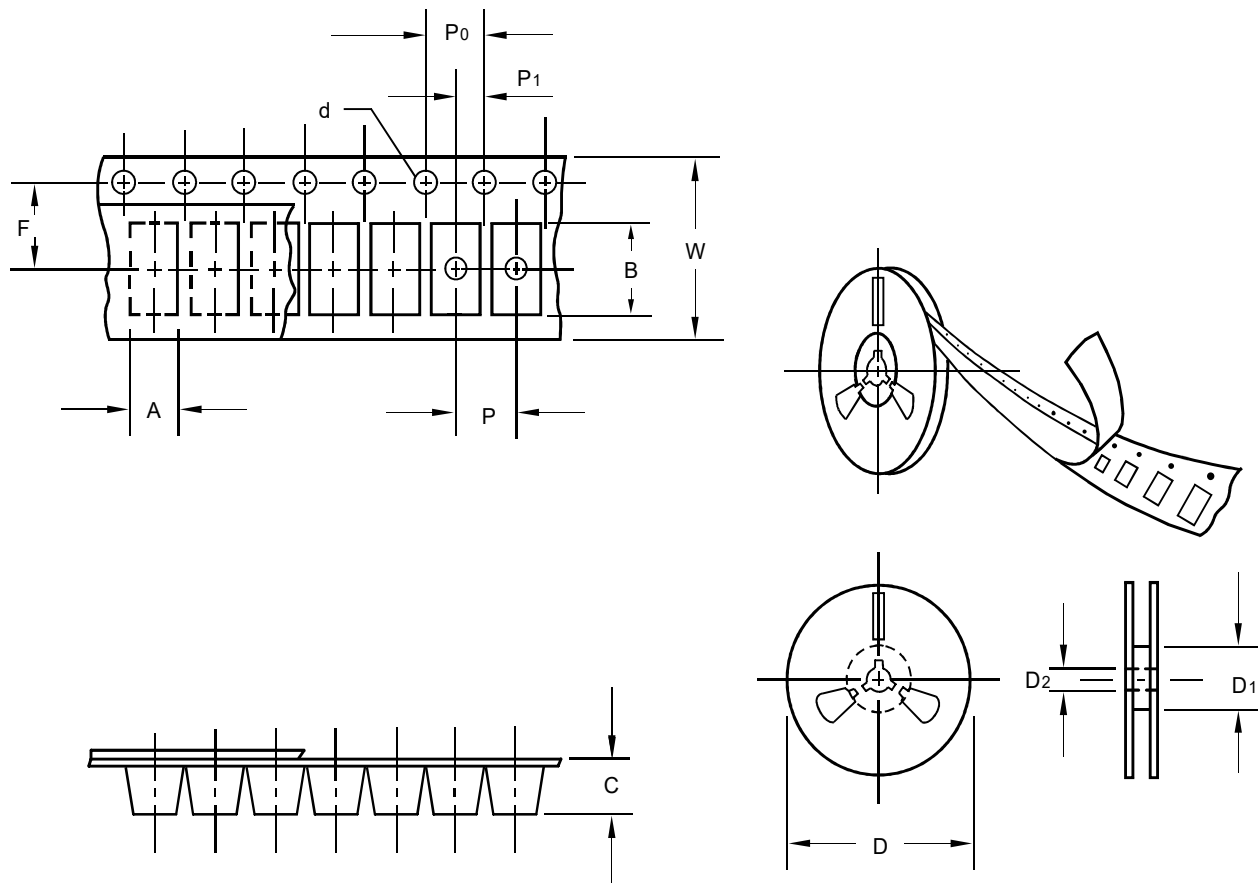
Suggested solder pad layout



- Note:
- 1.Controlling dimension:in millimeters.
 - 2.General tolerance:± 0.1 mm.
 - 3.The pad layout is for reference purposes only.

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Packing information



unit:mm

Item	Symbol	Tolerance	TO-252 (DPAK)
Carrier width	A	0.1	6.90
Carrier length	B	0.1	10.50
Carrier depth	C	0.1	2.78
Sprocket hole	d	0.1	1.50
13" Reel outside diameter	D	2.0	330.00
13" Reel inner diameter	D1	min	98.00
7" Reel outside diameter	D	2.0	-
7" Reel inner diameter	D1	min	-
Feed hole diameter	D2	0.5	13.00
Punch hole position	F	0.1	7.50
Punch hole pitch	P	0.1	8.00
Sprocket hole pitch	P0	0.1	4.00
Embossment center	P1	0.1	2.00
Tape width	W	0.3	16.00

Note: Devices are packed in accordance with EIA standard RS-481-A and specifications listed above.

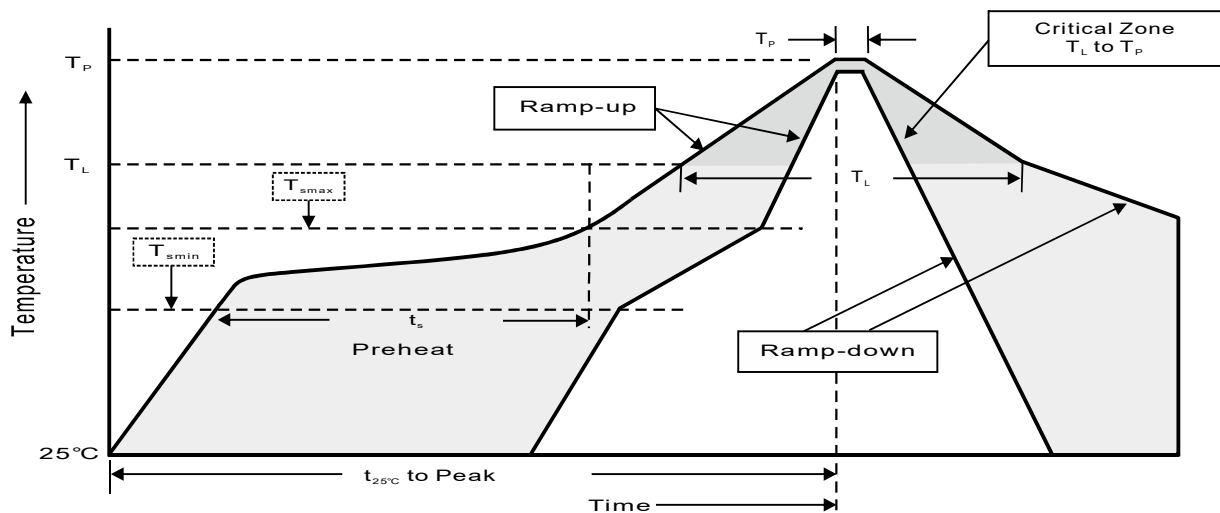
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Reel packing

PACKAGE	REEL SIZE	REEL (pcs)	COMPONENT SPACING (m/m)	BOX (pcs)	INNER BOX (m/m)	REEL DIA, (m/m)	CARTON SIZE (m/m)	CARTON (pcs)
TO-252 (DPAK)	13"	2,500	4.0	5,000	335*335*38	178	350*350*225	25,000

Suggested thermal profiles for soldering processes

- 1.Storage environment: Temperature = 5°C ~ 40°C Humidity = 55%, ±25%
- 2.Reflow soldering of surface-mount devices



3.Reflow soldering

Profile feature	Soldering condition
Average ramp-up rate (T_L to T_P)	< 3 °C/sec
Preheat - Temperature Min (T_{min}) - Temperature Max (T_{max}) - Time (Min to Max) (t_s)	150°C 200°C 60 ~ 120 sec
T_{smax} to T_L - Ramp-up rate	< 3 °C/sec
Time maintained above : - Temperature (T_L) - Time (T_L)	217°C 60 ~ 260 sec
Peak temperature (T_P)	255 °C -0/+5°C
Time with 5°C of actual peak temperature (T_P)	10 ~30 sec
Ramp-down rate	< 6 °C/sec
Time 25°C to peak temperature	< 6 minutes

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High reliability test capabilities

Item Test	Conditions	Reference
1. MSL Preconditioning	24hr bake@125°C+168hrs@85°C /85%RH+3xIR@260°C+1flux immersion+alcohol+DI H2O rinse	JESD22-A113
2. High Temperature Reverse Bias	$V_{DS}=V_{DS}^*80\%$ ($T_J=T_J \text{ max.}$) Test Duration:1000hrs	JESD22-A108
3. High Temperature Storage Life	$T_a=150^\circ\text{C}$ Test Duration:1000hrs	JESD22 A-103
4. Temperature Cycle	-55°C (15min) to 150°C (15min) Test Cycles:1000cycles	JESD22 A-104
5. Autoclave	$P=2\text{atm}$ $T_a=121^\circ\text{C}$ RH=100% Test Duration:96hrs	JESD22 A-102
6. Solderability	$245\pm5^\circ\text{C}$ for 5sec	J-STD-002
7. Moisture Resistance	$T_a=85^\circ\text{C}$ /85% Relative humidity Test Duration:1000hrs	MIL-STD-750E METHOD 1021.2
8. Resistance To Solder Heat	$260\pm5^\circ\text{C}$ for 10sec	JESD22 B-106
9. High Temperature High Humidity Reverse Bias	$T_a=85^\circ\text{C}$, 85%RH, $V_{DS}=80\%$ rated V_{DS} Test Duration: 1000hrs	JESD22-A101